

**Search Notes**

Application/Control No.

10/767,614

Examiner

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Applicant(s)/Patent under  
Reexamination

OGAWA, HIDEHIKO

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner
358	1.15, 402, 440	6/6/2005	TDL
379	100.01	6/6/2005	TDL
379	100.08	6/6/2005	TDL
379	100.13	6/6/2005	TDL
379	100.17	6/6/2005	TDL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR